S	earch	Notes	

Application/Contro	ol No.	Applicant(s)/Patent under Reexamination	
10/500,705		VAN DYK ET AL.	
Examiner		Art Unit	
John D. Holman		3643	

SEARCHED			
Class	Subclass	Date	Examiner
102	323	3/24/2006	JDH
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY	<b>'</b> )
	DATE	EXMR
PCT references used	3/24/2006	JDH